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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/001,709	SAIKI ET AL.	
Examiner	Art Unit	
A. Sefer	2826	

	SEARCHED				
Class	Subclass	Date	Examiner		
349	96	11/24/2006	AS		
359	485	11/24/2006	AS		
	499-500	11/24/2006	AS		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Search update	11/24/2006	AS
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